


<p style="text-align: center;">Search Notes</p> 	<p>Application/Control No.</p> <p>10613015</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>LEE, CHUL-HEE</p>
	<p>Examiner</p> <p>Gauthier, Gerald</p>	<p>Art Unit</p> <p>2614</p>

SEARCHED			
Class	Subclass	Date	Examiner
370	352	1/25/2008	GG
370	352, 356, 395.6	7/23/2008	GG
725	114	7/23/2008	GG

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB)	1/25/2008	GG
Inventor's Name Search	7/23/2008	GG
EAST (US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB)	7/23/2008	GG

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
370	352, 356, 395.6	7/23/2008	GG
725	114	7/23/2008	GG
	Interference Search History (see attached)	7/23/2008	GG